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<b>QUERY CONTROL FORM</b>			<b>RTIS USE ONLY</b>		
Application No.	101020,208	Prepared by	NH	Tracking Number	05894361
Examiner-GAU	Auduong-2818	Date	2-17-4	Week Date	01/26/04
		No. of queries	1	JFW	

**JACKET**

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

<b>SPECIFICATION</b>	<b>MESSAGE</b>
	PTO-1449: Please either initial or line through citations. Copy provided for reference.
<b>CLAIMS</b>	initials NH
	Thankyou
<b>RESPONSE</b>	initials



# Electronic Information Disclosure Statement

## System and Method to Screen Defect Related Reliability Failures in CMOS SRMAS

Application:   
10/020208

Confirmation: 7966

Applicant(s): Surya Bhattacharya

Docket Number: 1875.0330001

Group Art Unit: 2818

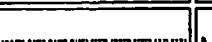
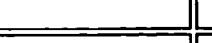
Examiner:

search string: ( 5745415 or 5661729 or 6154403 or 6115304 or 6081464 or 603816P ).pn

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### US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Citation No.	Patent Number	Date	Bar Code	Patentee	Class	Subclass
	P01	5745415	1998-04-28		Marr	365/201	
	P02	5661729	1997-08-26		Miyazaki et al.	714/719	
	P03	6154403	2000-11-28		Tanzawa et al.	365/203	
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		27			
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## Signature

Examiner Name	Date
Leanne Sekwong	5/03